

Sub-Picosecond Non-Equilibrium States in the Amorphous Phase of GeTe

Paloma Martinez^{a*}, Valérie Blanchet^a, Dominique Descamp^a, Jean-Baptiste Dory^b, Stéphane Petit^a, Jean-Yves Raty^{b,c}, Pierre Noé^b, Jérôme Gaudin^a

- CELIA, Université de Bordeaux, CEA, CNRS, UMR 5107, 351 Cours de la Libération, F-33405 Talence, France
- Université Grenoble Alpes, CEA, LETI, 17 rue des Martyrs, F-38000 Grenoble Cedex 9, France
- FRS-FNRS and CESAM, University of Liège, Allée du 6 Août 19, 4000 Sart-Tilman, Belgium

* email : paloma.martinez@u-bordeaux.fr, jerome.gaudin@u-bordeaux.fr

The sub-picosecond response of amorphous Germanium Telluride 500 nm thin film to a 30 femtosecond laser excitation is investigated using time-resolved 2 colors frequency domain interferometry (FDI) at the Aurore laser facility in University of Bordeaux [1]. The time-resolved measurements of surface dynamics, for impinging fluences ranging from $F = 16$ to 80 mJ/cm², reveals a dielectric response faster than 300 fs (Figure 1). For $F \geq 26$ mJ.cm², a shrinkage of the surface is observed and assigned to the propagation of a melted layer of a liquid phase that is confirmed by post-irradiation analysis [2]. The systematic *ab initio* molecular dynamics (AIMD) simulations in non-equilibrium conditions (Figure 1) allow us to retrieve the atomic configurations for ionic temperature (T_i) from 300 K to 1100 K and width of the electron distribution from 0.001 eV to 1.0 eV (T_e). Local order of the structures is characterized by in-depth analysis of the angle distribution, phonon modes and pair distribution function which evidence a transition towards a new amorphous electronic excited state close in bonding/structure to the liquid state. Our results shed a new light on the optically highly excited states in chalcogenide materials involved in both important processes in non-equilibrium conditions: phase-change materials in memory device and Ovonic threshold switching phenomenon induced by static field [3].

[1] [N. Fedorov et al., Review of Scientific Instruments 91, 105104 \(2020\)](#)

[2] [P. Martinez et al., Adv. Mater., 32, 2003032 \(2020\)](#)

[3] [P. Noé et al., Science Advances, 6, 9 eaay 2830 \(2020\)](#)

Figure 1: Left panel : Relative variation of the real part of the dielectric constant of GeTe films as a function of time for increasing laser fluences. Right panel - top: Angular limited three-body correlation (ALTBC) map of the AIMD simulation at $T_i=600$ K, $T_e = 0.3$ eV - Bottom: Corresponding structure, Ge and Te atoms depicted in red and blue respectively.

